

Electronic Instruments in 1L35

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For Signatone probe station:

- Agilent 4156C Semiconductor Parameter Analyzer



For Rucker & Kolls probe station:

- Agilent 4156C Semiconductor Parameter Analyzer with Pulse Generation Unit



For LakeShore and high-temperature probe stations :

- (2) Keithley 2636 Dual-channel System SourceMeter (quad-channel total)

Off-the-shelf instrumentation:

- Stanford Research Systems SR785 Dual-channel dynamic signal analyzer
- Stanford Research Systems SR830 DSP Dual Phase Lock-In Amplifier
- Agilent Agilent E4980A Precision LCR Meter
- Keithley 2635 single-channel SourceMeter
- Agilent DSO6012A Oscilloscope: 100 MHz, 2 channels
- Agilent 34410A Digital Multimeter, 6½ Digit
- Agilent E3645A 80W Power Supply, 35V, 2.2A or 60V, 1.3A



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